



## CS10J65 A4

### General Description:

CS10J65 A4, the silicon N-channel Enhanced MOSFETs, is obtained by the super junction technology which reduces the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package type is TO-252, which accords with the RoHS standard.

### Features:

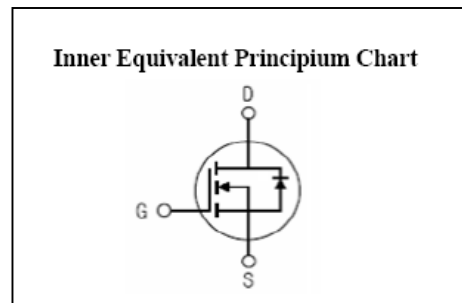
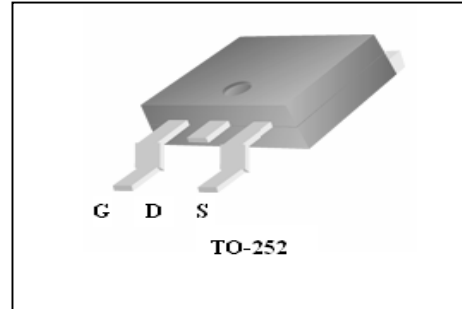
- | Fast Switching
- | Low Gate Charge
- | Low Reverse transfer capacitances
- | 100% Single Pulse avalanche energy Test

### Applications:

- | Power switch circuit of adaptor and charger.

**Absolute** (T<sub>c</sub>= 25°C unless otherwise specified):

V <sub>DSS</sub>	650	V
I <sub>D</sub>	10	A
P <sub>D</sub> (T <sub>c</sub> =25°C)	62	W
R <sub>DS(ON)max</sub>	0.62	Ω



Symbol	Parameter	Rating	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	650	V
I <sub>D</sub>	Continuous Drain Current	10	A
I <sub>DM</sub> <sup>a1</sup>	Pulsed Drain Current	30	A
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V
E <sub>AS</sub> <sup>a2</sup>	Single Pulse Avalanche Energy	50	mJ
dv/dt <sup>a3</sup>	Peak Diode Recovery dv/dt	5.0	V/ns
P <sub>D</sub>	Power Dissipation	62	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	-55...+150	°C

**Electrical Characteristics** (Tc= 25°C unless otherwise specified):

<b>OFF Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	650	--	--	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 25°C	--	--	1	μA
		V <sub>DS</sub> =520V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 125°C	--	--	100	
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> =+30V	--	--	100	nA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> =-30V	--	--	-100	nA

<b>ON Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DS(ON)</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V,I <sub>D</sub> =3A	--	0.54	0.62	Ω
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5		4	V

<b>Dynamic Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A	--	5.6	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V V <sub>DS</sub> = 50V f = 1.0MHz	--	450	--	pF
C <sub>oss</sub>	Output Capacitance		--	63	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	3.7	--	

<b>Resistive Switching Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	I <sub>D</sub> = 7 A V <sub>DD</sub> = 300V R <sub>G</sub> =25Ω	--	14	31	ns
t <sub>r</sub>	Rise Time		--	32	66	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	53	109	
t <sub>f</sub>	Fall Time		--	15	32	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> = 7 A V <sub>DD</sub> =480V V <sub>GS</sub> = 10V	--	10	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	2	--	
Q <sub>gd</sub>	Gate to Drain (“Miller”)Charge		--	3.7	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)		--		10	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--		20	A
$V_{SD}$	Diode Forward Voltage	$I_S=7A, V_{GS}=0V$	--	0.9	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_F=I_S$	--	400		ns
$Q_{rr}$	Reverse Recovery Charge	$I_F/dt=100A/us$	--	1.5		uC

Symbol	Parameter	Max.	Units
$R_{\theta JC}$	Junction-to-Case	2.0	°C/W
$R_{\theta JA}$	Junction-to-Ambient	100	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

<sup>a2</sup>:  $L=10.0mH, R_g=25\ \Omega, V_{dd}=50V, \text{Start } T_j=25^\circ C$

Characteristics Curve:

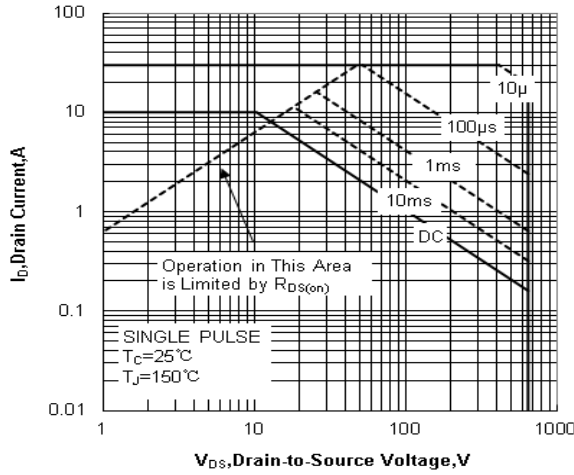


Figure.1 Maximum Forward Bias Safe Operating Area

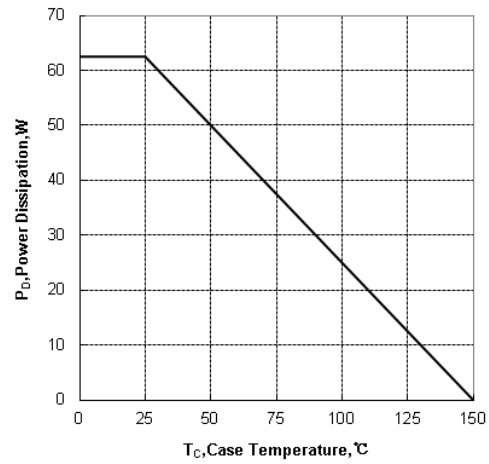


Figure.2 Maximum Power Dissipation vs Case Temperature

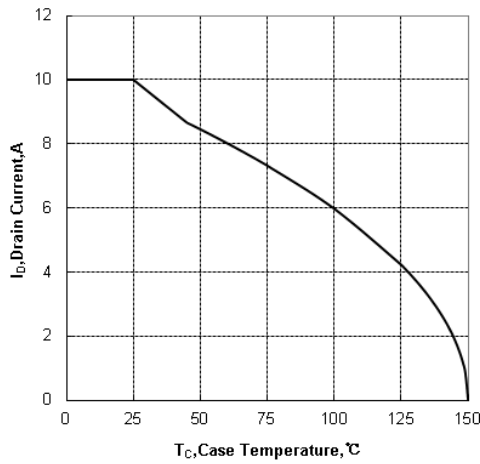


Figure.3 Maximum Continuous Drain Current vs Case Temperature

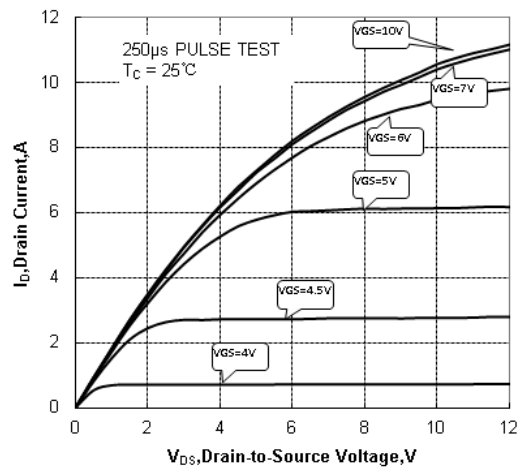


Figure.4 Typical Output Characteristics

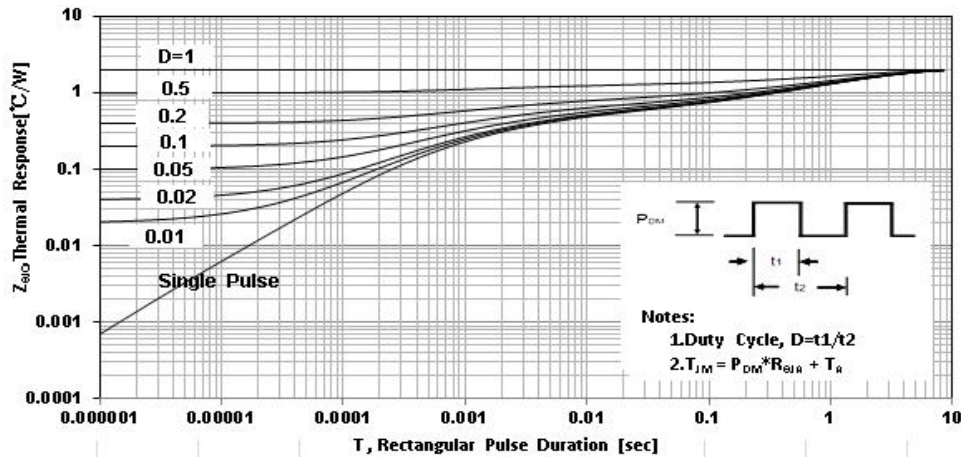


Figure.5 Maximum Effective Thermal Impedance, Junction to Case

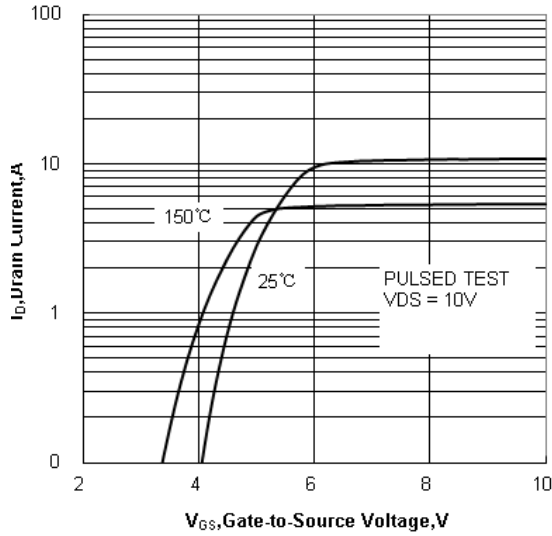


Figure.6 Typical Transfer Characteristics

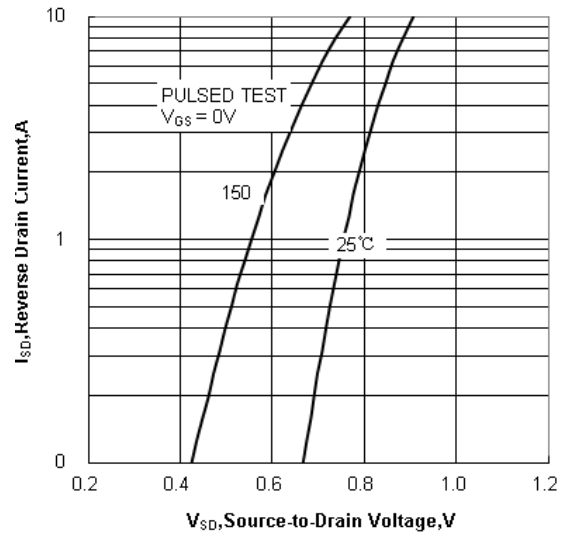


Figure.7 Typical Body Diode Transfer Characteristics

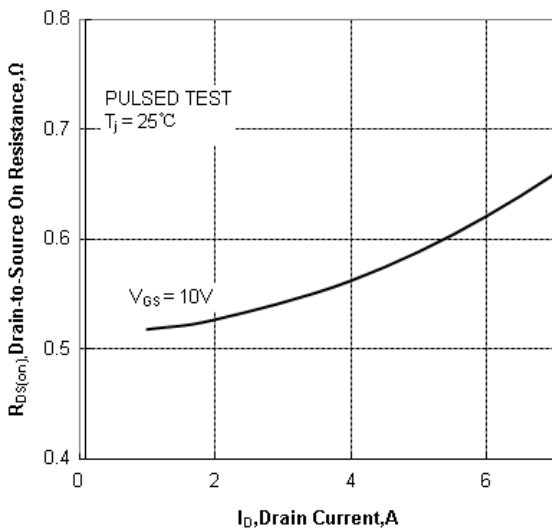


Figure.8 Typical Drain to Source ON Resistance vs Drain Current

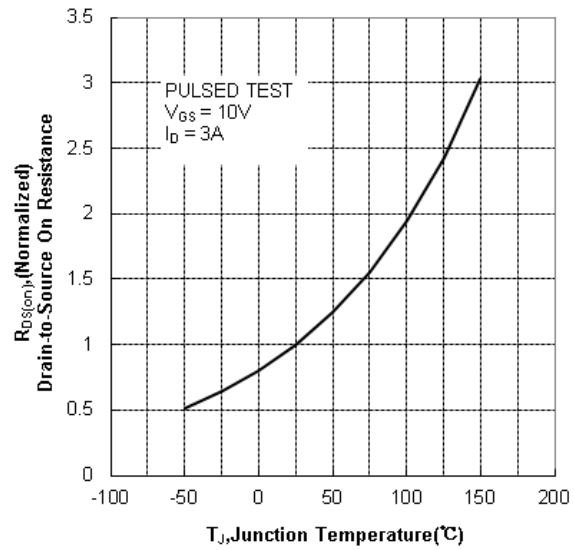


Figure.9 Typical Drain to Source on Resistance vs Junction Temperature

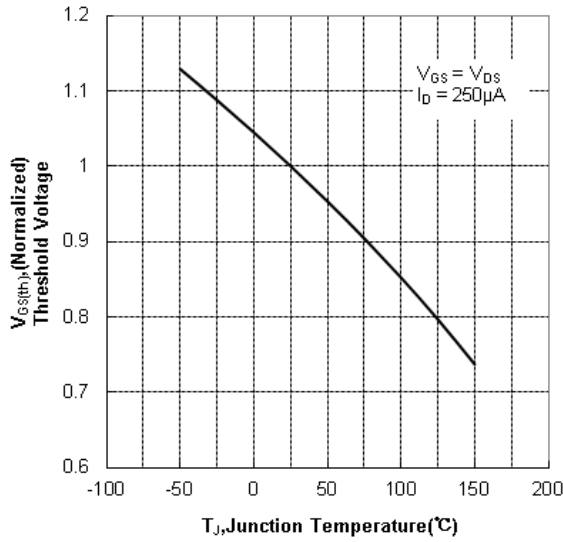


Figure.10 Typical Theshold Voltage vs Junction Temperatur

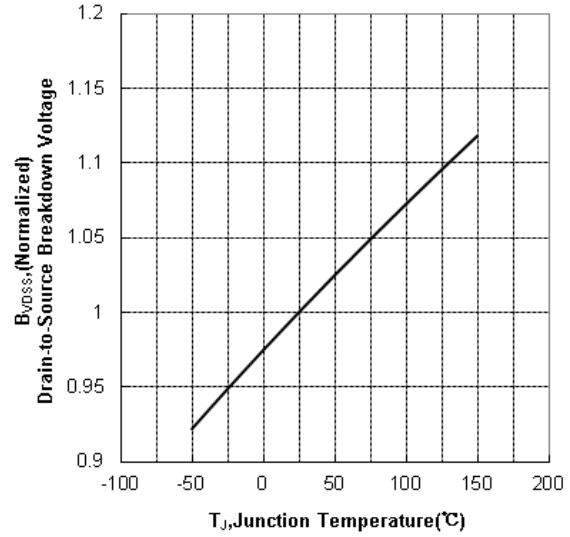


Figure 11 Typical Breakdown Voltage vs Junction Temperature

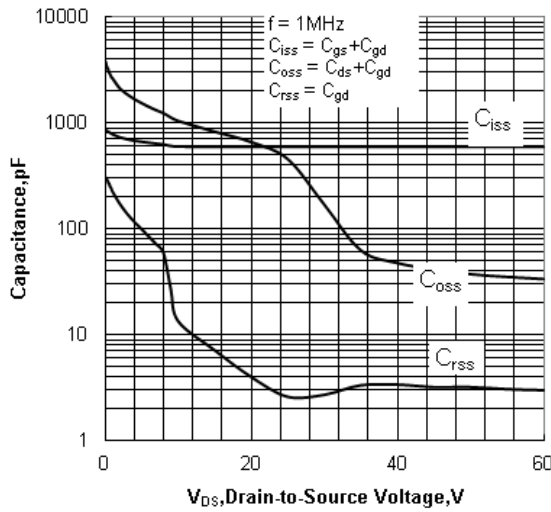


Figure.12 Typical Capacitance vs Drain to Source Voltage

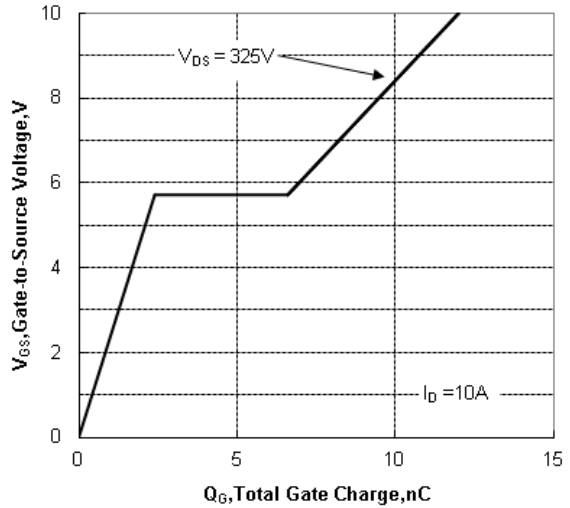


Figure.13 Typical Gate Charge vs Gate to Source Voltage

### Test Circuit and Waveform

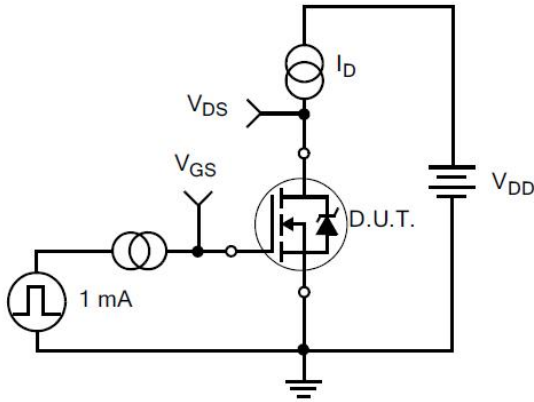


Figure 17. Gate Charge Test Circuit

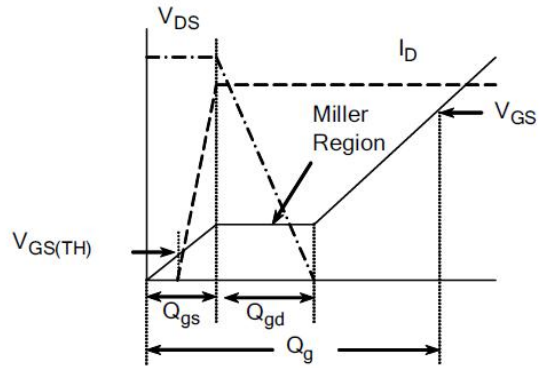


Figure 18. Gate Charge Waveform

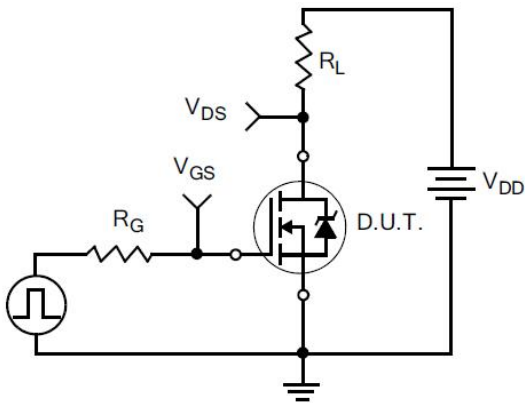


Figure 19. Resistive Switching Test Circuit

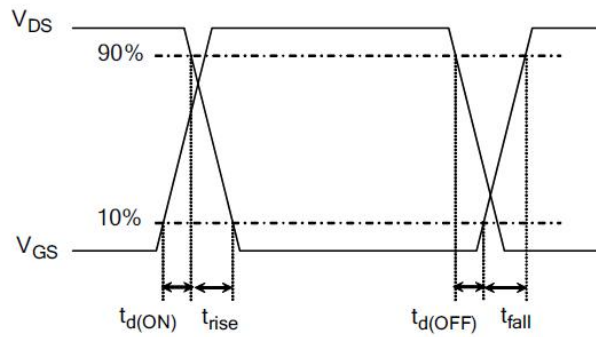


Figure 20. Resistive Switching Waveforms

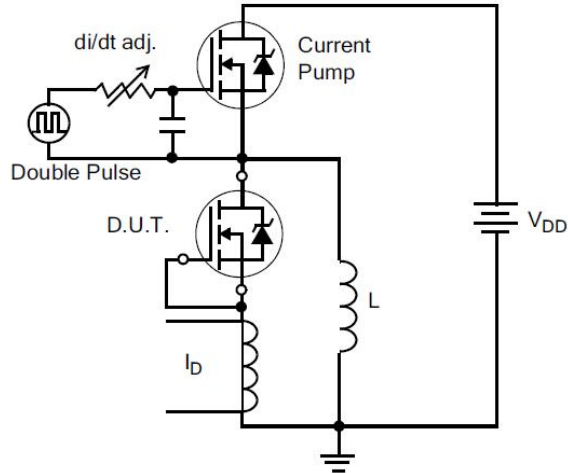


Figure 21. Diode Reverse Recovery Test Circuit

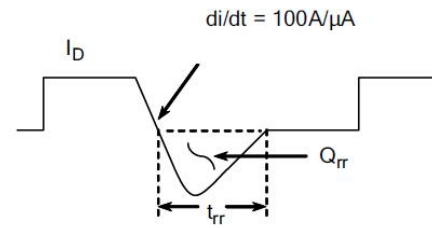


Figure 22. Diode Reverse Recovery Waveform

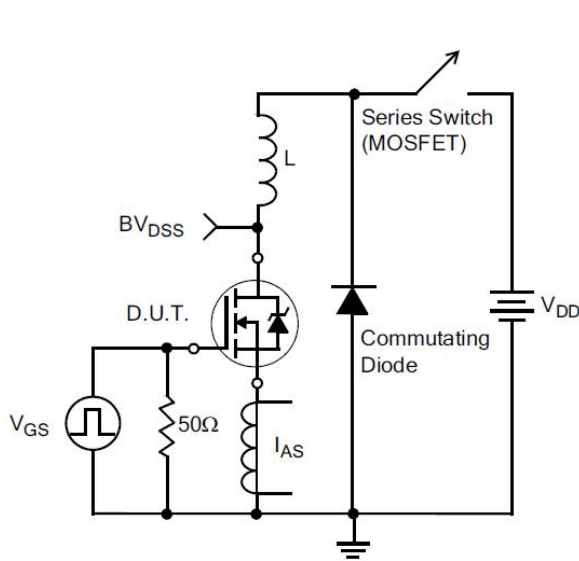


Figure 23. Unclamped Inductive Switching Test Circuit

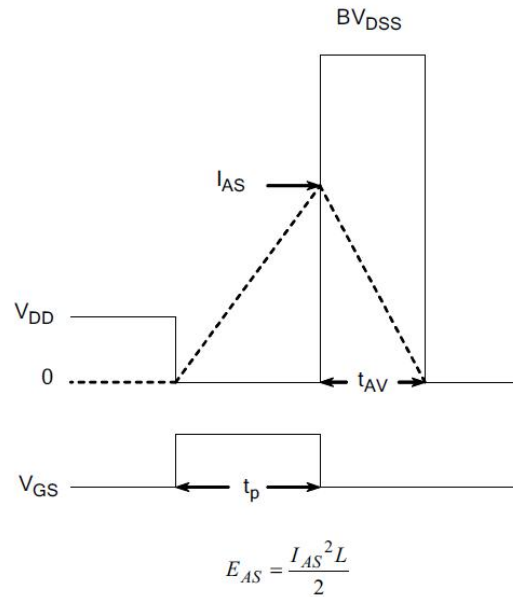
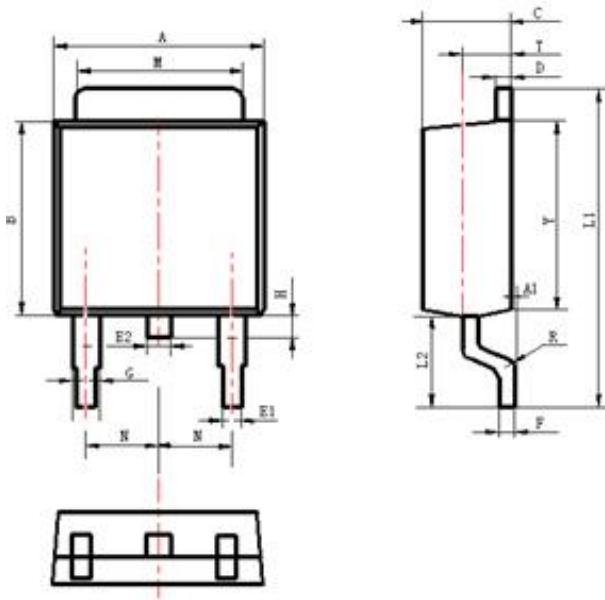


Figure 24. Unclamped Inductive Switching Waveforms



**Package Information:**



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
A1	0	0.13
B	5.70	6.30
C	2.10	2.50
D	0.30	0.60
E1	0.60	0.90
E2	0.70	1.00
F	0.30	0.60
G	0.70	1.00
L1	9.60	10.30
L2	2.70	3.10
H	0.60	1.00
M	5.10	5.50
N	2.09	2.49
R	0.3	
T	1.40	1.60
Y	5.10	6.30

TO-252 Package

